

[54] MULTIMETER

D. 253,227 10/1979 Buck D10/78

[75] Inventor: Masahiro Tanabe, Tokyo, Japan

OTHER PUBLICATIONS

[73] Assignee: Akigawa Electronic Corporation, Tokyo, Japan

Amprobe Inst. Test. Equip. Cat. 9/78, p. 6—Multimeter at top right.
Scientific Educational Products—Multimeter on front.

[**] Term: 14 years

Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Fleit, Jacobson & Cohn

[21] Appl. No.: 164,145

[22] Filed: Jun. 30, 1980

[57] CLAIM

[30] Foreign Application Priority Data

The ornamental design for multimeter, substantially as described and shown.

Feb. 8, 1980 [JP] Japan 55-4228

[51] Int. Cl. D10-04

DESCRIPTION

[52] U.S. Cl. D10/78

[58] Field of Search D10/75, 78, 46, 57;
324/73, 76 R, 115, 156

FIG. 1 is a front perspective view of a multimeter showing my new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a left side elevational view thereof;
FIG. 4 is a right side elevational view thereof;
FIG. 5 is a rear elevational view thereof;
FIG. 6 is a top plan view thereof; and
FIG. 7 is a bottom plan view thereof.

[56] References Cited

U.S. PATENT DOCUMENTS

D. 223,196 3/1972 Andreaggi D10/78
D. 246,767 12/1977 Needham D10/78

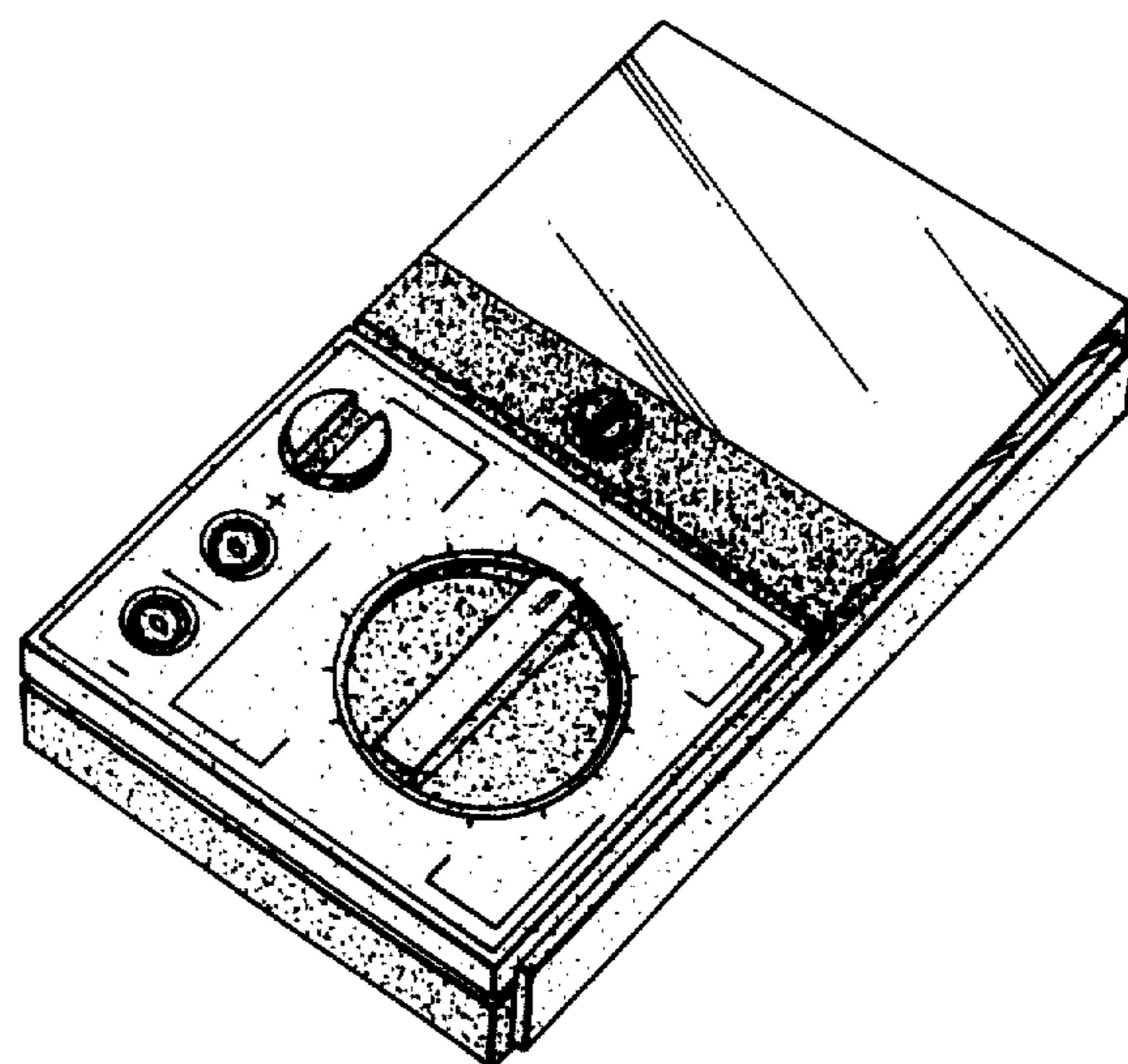


FIG. 1

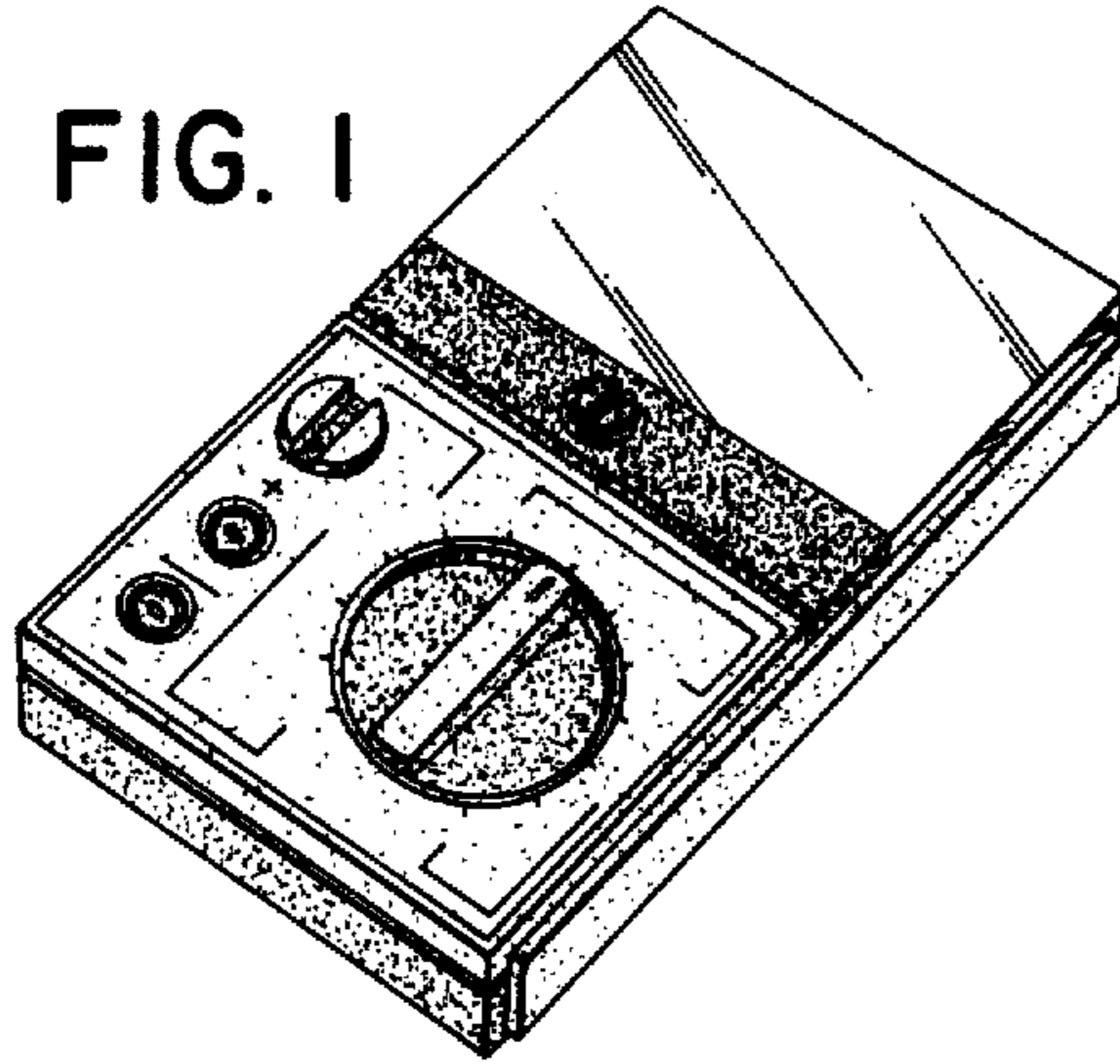


FIG. 2

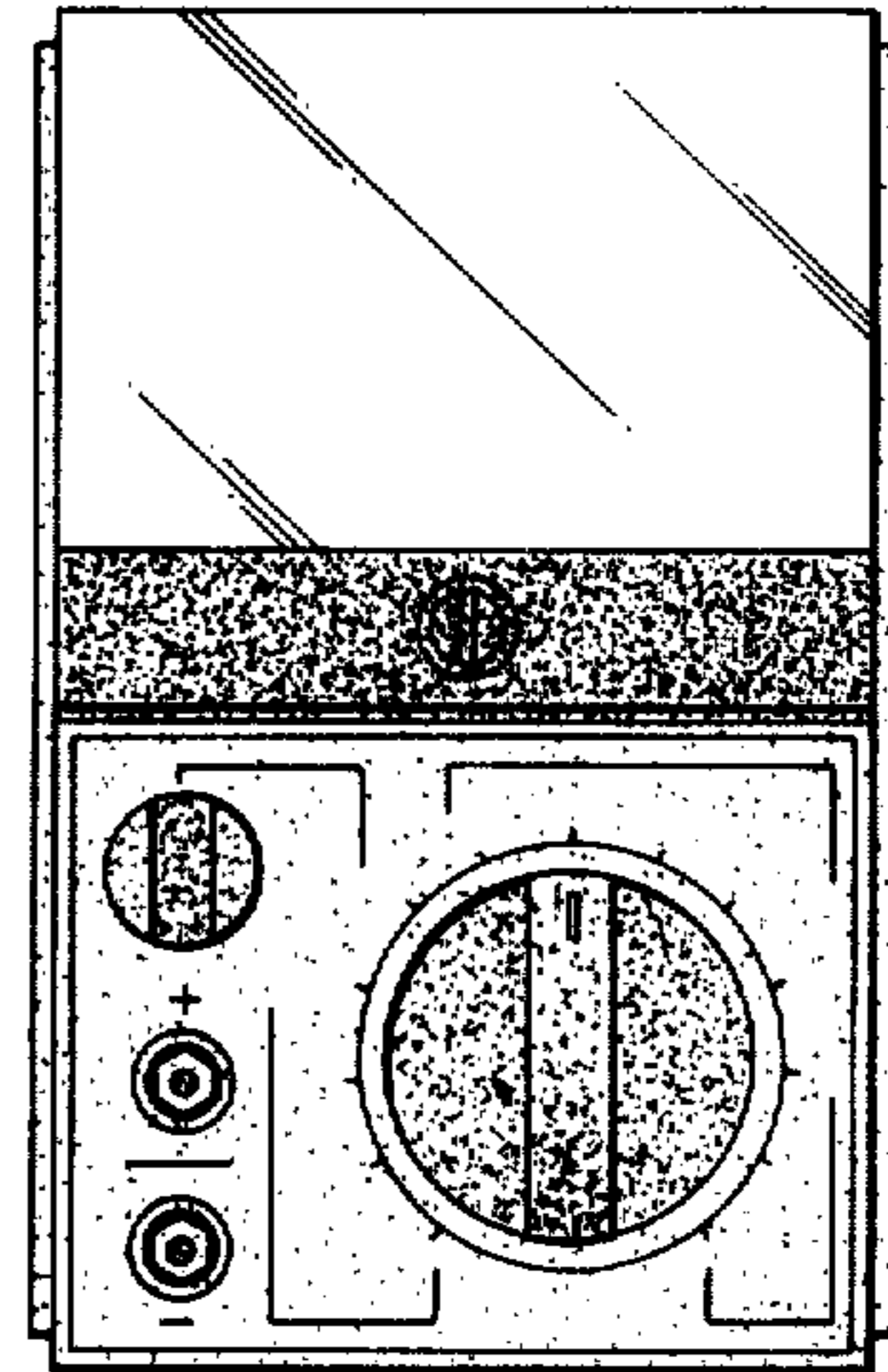


FIG. 3

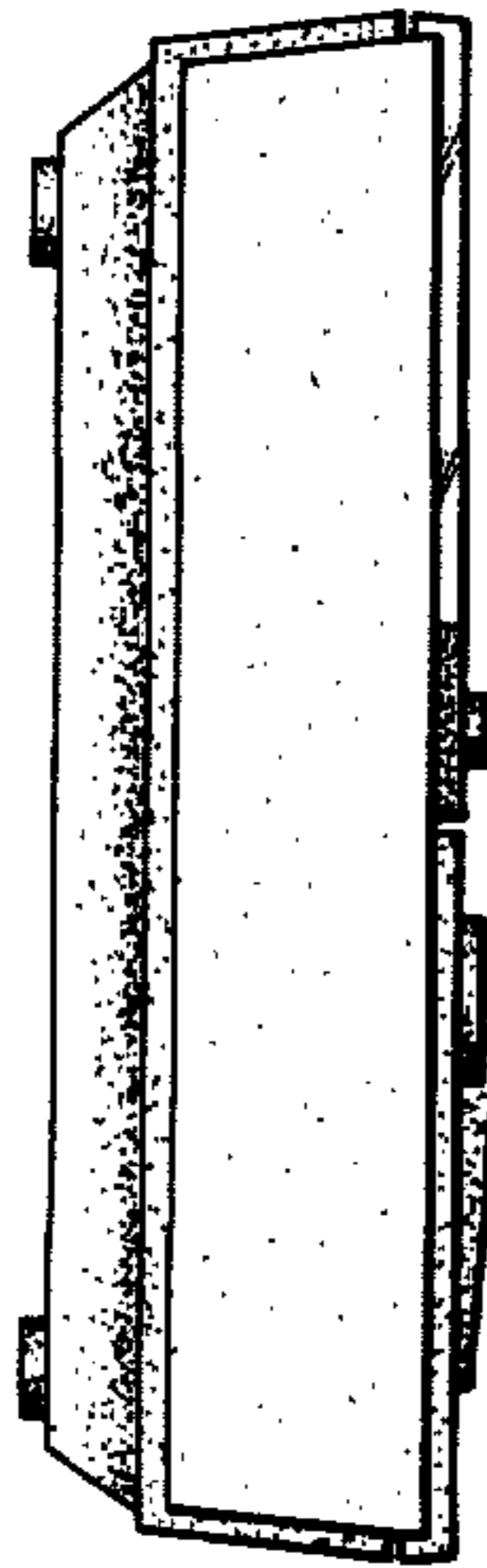


FIG. 4

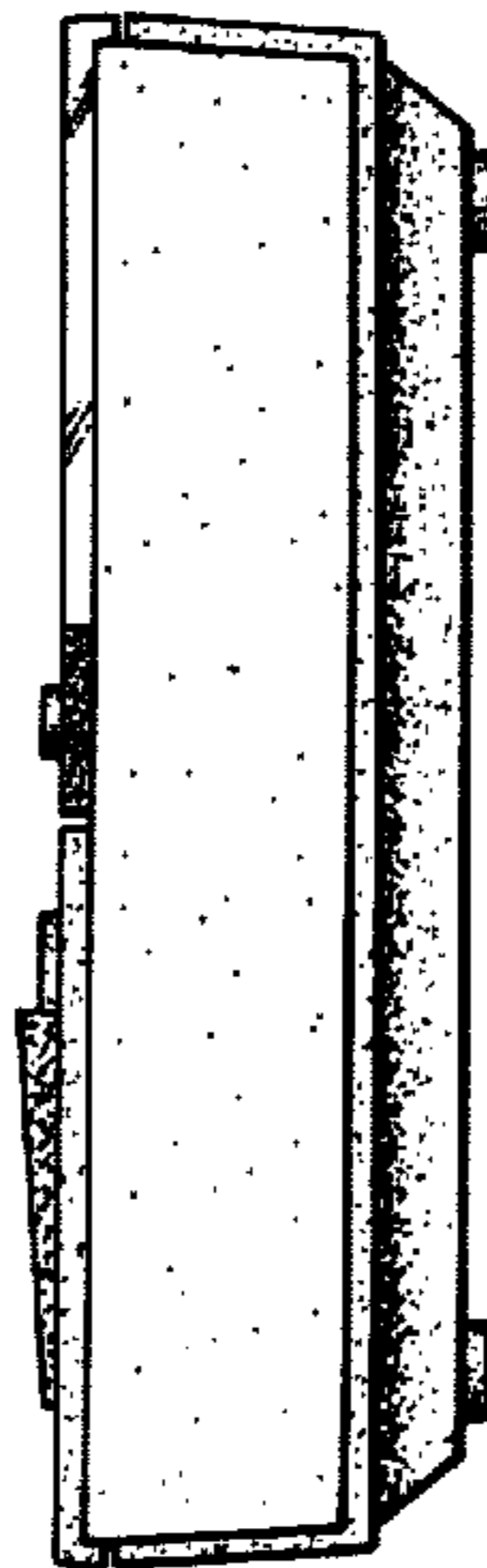


FIG. 5

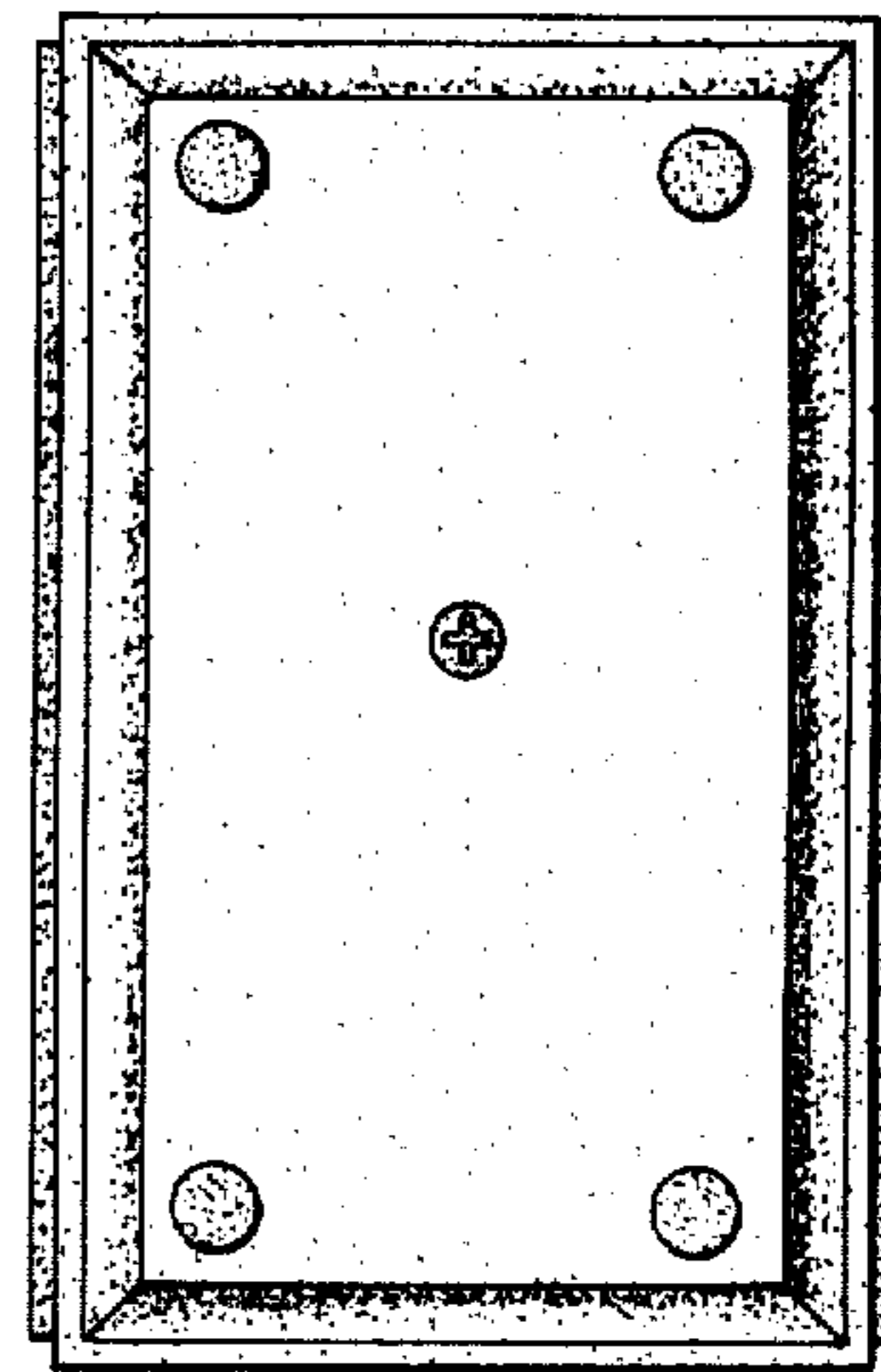


FIG. 7

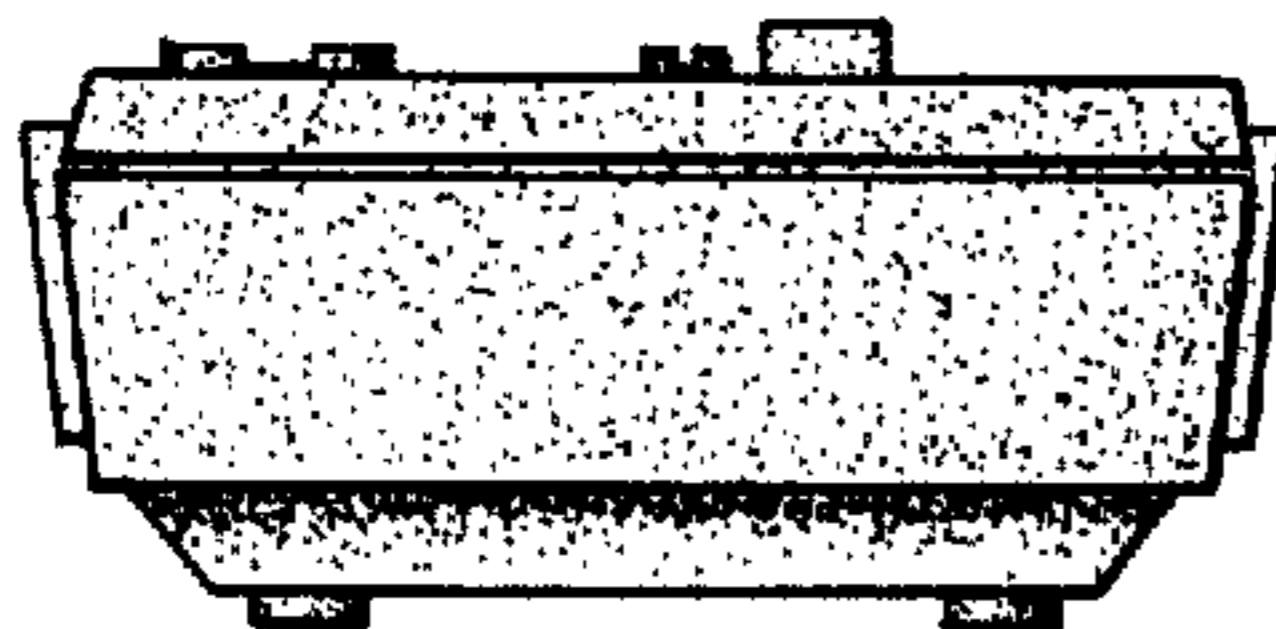


FIG. 6

